 Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/796,175	ARAKAWA ET AL.	
Examiner	Art Unit	
Vicun Wu	2165	

	SEAR	CHED	
Class	Subclass	Date	Examiner
70 7 1	1,2,3,4 5,6,7,8 9,10, 100	7/20/05	1
	104.1		
711	112 114		
	147154		
714	6, 13	\rightarrow	· .
updated	Sorroh	11/2/05	yw
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
7.7	204	14/7/05	yw
707	201		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventor search (double patenting) uspto uspgpub usocr epo jpo ibmtech derwent	7./20/05	1	
acm leee citeseer internet Search stratagy attached			
m) dated sench	11/7/05	br	
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